
Referenčni pogoji in postopki za preskušanje industrijskih in procesnih merilnih oddajnikov - 3. del: Posebni postopki za oddajnike temperature

Reference conditions and procedures for testing industrial and process measurement transmitters - Part 3: Specific procedures for temperature transmitters

Referenzbedingungen und Testmethoden für Industrie- und Prozessmessgrößenumformer - Teil 3: Spezielle Testmethoden für Temperaturmessumformer

Conditions de référence et procédures pour l'essai des transmetteurs de mesure industrielle et de processus - Partie 3: Procédures spécifiques pour les transmetteurs de température

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TITLE:

Reference conditions and procedures for testing industrial and process measurement transmitters - Part 3: Specific procedures for temperature transmitters

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CONTENTS

FOREWORD	5
INTRODUCTION	7
1 Scope	9
2 Normative references	9
3 Terms and definitions and abbreviated terms	10
3.1 Terms and definitions	10
3.1.1 Emissivity setting	10
3.1.2 Exposure time	10
3.1.3 Field-of-view	10
3.1.4 International Temperature Scale of 1990 (ITS-90)	10
3.1.5 Measuring distance	10
3.1.6 Noise equivalent temperature difference	11
3.1.7 Radiation temperature transmitter	11
3.1.8 Reference junction compensation (RJC)	11
3.1.9 Resistance temperature detector (RTD)	11
3.1.10 Short-term stability	11
3.1.11 Size-of-source effect	11
3.1.12 Spectral range	11
3.1.13 Thermocouple (TC)	11
3.1.14 Warm-up time	12
3.2 Abbreviated terms	12
4 General description of the device	12
5 Reference test conditions	12
6 Test procedures	12
6.1 General	12
6.1.1 Temperature Process Measurement Transmitter (PMT) for TC and RTD	12
6.1.2 Process Measurement Transmitter for Radiation temperature measurement	14
6.2 Type tests at standard and operating reference test conditions	14
6.2.1 General	14
6.2.2 Methods for inaccuracy determination in acceptance and routine tests	15

36	6.2.3	Specific test procedures for radiation temperature transmitter	16
37	7	Test report.....	20
38	7.1	General	20
39	7.2	Total probable error (TPE)	20
40	Annex A.....		21
41	A.1	Temperature PMT (Contact thermometers)	21
42	A.2	Temperature PMT (Radiation temperature transmitter)	21
43	Annex B.....		23
44	B.1	Properties of temperature transmitter classes	23
45	B.1.1	Contact temperature transmitter.....	23
46	B.1.2	Radiation (Non-contact) temperature transmitter	25
47	Annex C.....		27
48	C.1	Determination of the Inaccuracy	27
49	C.2	Determination of the Noise equivalent temperature difference (NETD)	27
50	C.3	Field-of-view (target size).....	28
51	C.4	Determination of the Size-of-Source-Effect (SSE).....	28
52	C.5	Influence of the internal instrument or ambient temperature	
53		(temperature parameter)	29
54	C.6	Short-term stability	30
55	C.7	Exposure time	31
56	C.8	Warm-Up time.....	32
57	Annex D		34
58	Bibliography		36
59			
60	Figure 1	Schematic example of test set-up for temperature measurement	
61		transmitters	13
62	Figure 2	Examples of terminals connection for RTD and TC	13
63	Figure 3	Schematic example of a test set-up for radiation temperature	
64		transmitters	14
65	Figure 4	Example of measured error plot	16
66	Figure 5	Relative signal to a signal at a defined aperture size (source size) of	
67		100 mm in diameter for two infrared radiation temperature transmitters A and	
68		B versus the source diameter	17
69	Figure 6	Demonstration of the exposure time	19